

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



**High-voltage switchgear and controlgear –  
Part 101: Synthetic testing**

**Appareillage à haute tension –  
Partie 101: Essais synthétiques**

[IEC 62271-101:2012](https://standards.iteh.ai/standards/iec/62271-101:2012)

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## REDLINE VERSION

## VERSION REDLINE



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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

### HIGH-VOLTAGE SWITCHGEAR AND CONTROLGEAR –

#### Part 101: Synthetic testing

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**IEC 62271-101 edition 2.1 contains the second edition (2012-10) [documents 17A/1015/FDIS and 17A/1024/RVD], its amendment 1 (2017-11) [documents 17A/1149/FDIS and 17A/1154/RVD] and its corrigendum (2018-01).**

**In this Redline version, a vertical line in the margin shows where the technical content is modified by amendment 1. Additions are in green text, deletions are in strikethrough red text. A separate Final version with all changes accepted is available in this publication.**

International Standard IEC 62271-101 has been prepared by subcommittee 17A: High-voltage switchgear and controlgear, of IEC technical committee 17: Switchgear and controlgear.

This second edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the first edition:

- addition of the new rated voltages of 1 100 kV and 1 200 kV;
- revision of Annex F regarding circuit-breakers with opening resistors;
- alignment with the second edition of IEC 62271-100:2008 and its Amendment 1 (2012).

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This publication shall be read in conjunction with IEC 62271-100, published in 2008, to which it refers. The numbering of the subclauses of Clause 6 is the same as in IEC 62271-100. However, not all subclauses of IEC 62271-100 are addressed, merely those where synthetic testing has introduced changes.

A list of all the parts in the IEC 62271 series, under the general title *High-voltage switchgear and controlgear*, can be found on the IEC website.

The committee has decided that the contents of the base publication and its amendment will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
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